

<b>Notice of References Cited</b>	Application/Control No. 10/784,993	Applicant(s)/Patent Under Reexamination HOU, TIEN WANG	
	Examiner Rodney H. Bonck	Art Unit 3681	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0107793 A1	06-2004	Chiang, Douglas	074/572
	B	US-4,254,852	03-1981	Orozco, Hector M.	192/46
	C	US-1,566,378	12-1925	FREDERIC DEFORDT JULES	192/46
	D	US-1,429,196	09-1922	ANNIBALE DUGHERA	192/64
	E	US-5,690,202	11-1997	Myers, John E.	192/46
	F	US-4,727,965	03-1988	Zach et al.	192/46
	G	US-2004/0084272 A1	05-2004	Yoshiie et al.	192/046
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 522 983 A1	01-1993	EPO	Mercat et al.	-----
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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